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The In°uence of Temperature Variation on the Performance of Arrayed-Waveguide Grating Based on ARROW Structures

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Abstract | The in°uence of temperature variation on the performance of AWG based on ARROW structures is discussed. Design of temperature-insensitive ARROW-based AWG devices is reported. The passband shift can be reduced to 0.002 nm/K.

Index terms: integrated optics, antiresonant re°ecting optical waveguide, arrayed-waveguide grating, wavelength-division multiplexing, temperature variation.

1. Introduction

Wavelength multi/demultiplexers are key components in wavelength-division-multiplexing (WDM) systems. Among various con qurations, arrayed-waveguide grating (AWG) multi/demultiplexers are attractive owing to easy fabrication, mass production, small size, and the ability of integration [1]. In contrast to conventional waveguide structures, antiresonant re°ecting optical waveguides (ARROW's) utilizing antiresonant re°ection as guiding mechanism instead of total internal re°ection can perform low-loss single mode propagation with relatively large core size [2]. ARROW-based AWG demultiplexers have been proposed, but the temperature e®ect on their performance has not yet been discussed.

In this presentation, the in°uence of temperature variation on the performance of AWG based on ARROW structures is investigated. In order to reduce the temperature dependence, an overlay with a negative temperature coe± cient is introduced, since the temperature coe± cient for the original structure is positive. The improved design of temperature-insensitive ARROW-based AWG devices is reported.

2. Temperature Dependence of the ARROW-based AWG Performance

The 3-D Si-based ARROW structure used for AWG devices is shown in Fig. 1. It is a multi-layered structure with an ARROW con quration in the vertical direction (x) and a conventional waveguide structure along the lateral direction (y). The material of the core and the second cladding layer is $SiO₂$ $(n_c = n_l = 1.45)$ and the high-index $\overline{\ }$ rst cladding layer is poly-Si ($n_h = 3.50$). The free-space operating wavelength ₁₀ is 1.55 ¹m. To attain a low insertion loss for the ARROW-based AWG devices, whose optical path length is usually several centimeters, the thickness of the core layer is chosen to be 7:00 $^{\text{1}}$ m to keep the propagation loss of the vertical ARROW structure acceptably low. The thickness of the ¯rst and second cladding layers are found to be 0.12 and $3:50⁻¹$ m respectively, by satisfying the transverse antiresonant condition [2]

$$
d_{i} = \frac{0}{4n_{i}} \qquad 1 \qquad i \qquad \frac{n_{c}}{n_{i}} \qquad 1 \qquad 2 \qquad \mu \qquad 3 \qquad \eta_{2} \qquad \eta_{1} \qquad 4 \qquad \tau_{i} \qquad 1 = 2 \qquad \tau_{i} \qquad Q_{i} \qquad Q_{i} = 0; 1; 2; \text{etc}; \qquad (1)
$$

where $i = h_i$, and $d_{c;core}$ is the thickness of the core layer. For single-mode operation in the lateral y-direction, the thickness of the core layer in the lateral cladding regions $d_{\text{c,lead}}$ is chosen to be 4:80 ¹m. The e®ective index method (EIM) is used to analyze the 3-D waveguide structure.

To investigate the temperature dependence of the ARROW-based AWG performance, the temperature coe± cient of the refractive index of $SiO₂$ \Box (dn=dT = 7:93 £ 10ⁱ ⁶=K [3]) and Si (dn=dT = 160 £ 10ⁱ ⁶=K [4]) are introduced into the analysis. Fig. 2 shows the e®ective index of the fundamental mode of the vertical 2-D ARROW structure in the core region versus temperature. The slope of the curve dN_{eff} =dT can be found to be 7:96 £ 10ⁱ ⁶=K, which is relatively close to the temperature coe± cient of the refractive index of the core layer. As for the 3-D structure, the width of the core region W = $7 \text{ }^{\text{1}}\text{m}$, which will be the width of array waveguides, is considered. The analyzed results show that the e®ective index N_{eff} is 1.4445, propagation loss is 0.077 dB/cm, and the temperature dependence dN_{eff}=dT is 7:966 £ 10ⁱ ⁶=K.

The temperature dependence of the ARROW-based AWG performance, which can be described by the dependence of the pass wavelength on the temperature, could be expressed as

$$
\frac{d_s}{dT} = \int_c e^{H} \frac{1}{N_c} \frac{dN_c}{dT} + \frac{1}{C} \frac{dC}{dT} \frac{L}{dT} = \int_c e^{H} \frac{1}{N_c} \frac{dN_c}{dT} + e^{H}
$$
 (2)

where $\epsilon_{\rm c}$ is the central wavelength in free space, N_c is the e®ective index of the array waveguides, ϵL is the optical path length di®erence between adjacent array waveguides, and ® is the thermal expansion coe± cient of ¢ L de¯ned as

$$
^{\circledcirc} = \frac{1}{\mathfrak{C}} \frac{d\mathfrak{C}}{d\mathsf{T}} \cdot \tag{3}
$$

Since the thickness of the substrate is usually much greater than that of waveguide layers, the thermal expansion coe± cient [®] is mainly determined by that of the Si substrate ($\frac{8}{51}$ = 2:63 £ 10ⁱ ⁶=K [3]). Introducing the previous found values and the central wavelength $\varsigma_c = 1.55$ ¹m into Eq. (2), the temperature dependence of the pass wavelength of the proposed ARROW-based AWG is obtained as

$$
\frac{d_s}{dT} = 1:26 \text{ f } 10^{i} \text{ }^{5} \text{ }^{1} \text{m} = \text{K} = 1:26 \text{ f } 10^{i} \text{ }^{2} \text{nm} = \text{K}:
$$
 (4)

This value is quite near the temperature dependence of a conventional AWG (1:2 £ 10^{i} 2 nm/K [1]).

3. Design of Temperature-Insensitive ARROW-based AWG

The temperature dependence of the ARROW-based AWG must be reduced or eliminated to prevent the use of power-consuming temperature controllers. From Eq. (2), the athermal (temperatureinsensitive) condition can be obtained if

$$
^{\circledast} \text{sub} + \frac{1}{N_{\text{eff}}} \frac{dN_{\text{eff}}}{dT} = 0; \tag{5}
$$

where \mathcal{P}_{sub} is the thermal expansion coe± cient of the substrate. Since Si substrate has a positive thermal expansion coe \pm cient, it's required to $\bar{\ }$ nd a negative value of dN_{eff}=dT to satisfy the above equation. For this purpose, an additional overlay with a negative value of $dN_{\text{eff}} = dT$ is added on the original structure, as shown in Fig. 3. Here, silicone polymer is chosen and its refractive index and temperature coe± cient are 1.50 and μ 370 £ 10ⁱ ⁶=K [1], respectively. To have a negative value of dN_{eff}=dT and maintain low propagation loss, it can be found that the thickness of the silicone overlay $d_{add} = 0:60$ ¹m is suitable and then dN_{eff} =dT of the vertical 2-D ARROW structure in the core region becomes $\frac{1}{2}$ 5:09 £ 10ⁱ ⁶=K. Since the vertical 2-D structure in the core region has been changed, the thickness of the core layer in the lateral cladding regions is adjusted to be 5:50 ¹m to maintain single-mode operation in the lateral direction and low propagation loss.

Fig. 4 shows the fundamental-mode e®ective index of the proposed ARROW structure with a silicon overlay versus temperature. In comparison with Fig. 2, it can be seen that the variation of the e®ective index is signi¯cantly reduced. The temperature dependence of the wavelength shift of the ARROW-based AWG with and without a silicone overlay are displayed in Fig. 5. The overall wavelength shift of the proposed temperature-insensitive ARROW-based AWG within the temperature range of 0̄{50ª C is below 0.08 nm, and the temperature dependence of the channel pass wavelengths is reduced to 0.002 nm= $^{\pm}$ C, i.e., 0.002 nm/K.

4. Conclusion

The temperature dependence of the performance of AWG based on ARROW structures is analyzed. For the positive temperature dependence of the structure, a silicone overlay with a negative temperature coe± cient is used on top of the channel of the 3-D ARROW structure to reduce the temperature dependence. Based on the structure, a feasible design of temperature-insensitive ARROW-based AWG devices is reported. The pass wavelength shift can be signi¯cantly reduced from 0.0126 nm/K to 0.002 nm/K.

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Figure 1: The schematic view of 3-D ARROW structure for AWG devices.

Figure 2: The effective index of the vertical 2-D ARROW structure in the core region versus temperature.

Figure 3: 3-D ARROW structure with a silicone overlay on top of the core layer in the core region.

Figure 4: The temperature dependence of the effective index of the ARROW with a silicone overlay.

Figure 5: The wavelength shift versus temperature of ARROW-based AWG devices.